

Notice of References Cited	Application/Control No. 10/572,839		Applicant(s)/Patent Under Reexamination TANAKA, HIDEO	
	Examiner RICHARD H. KIM		Art Unit 2871	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,949,507	09-1999	Shimada et al.	349/113
*	B	US-7,176,994 b2	02-2007	Maeda et al.	349/113
*	C	US-2003/0086036 A1	05-2003	Yang et al.	349/113
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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